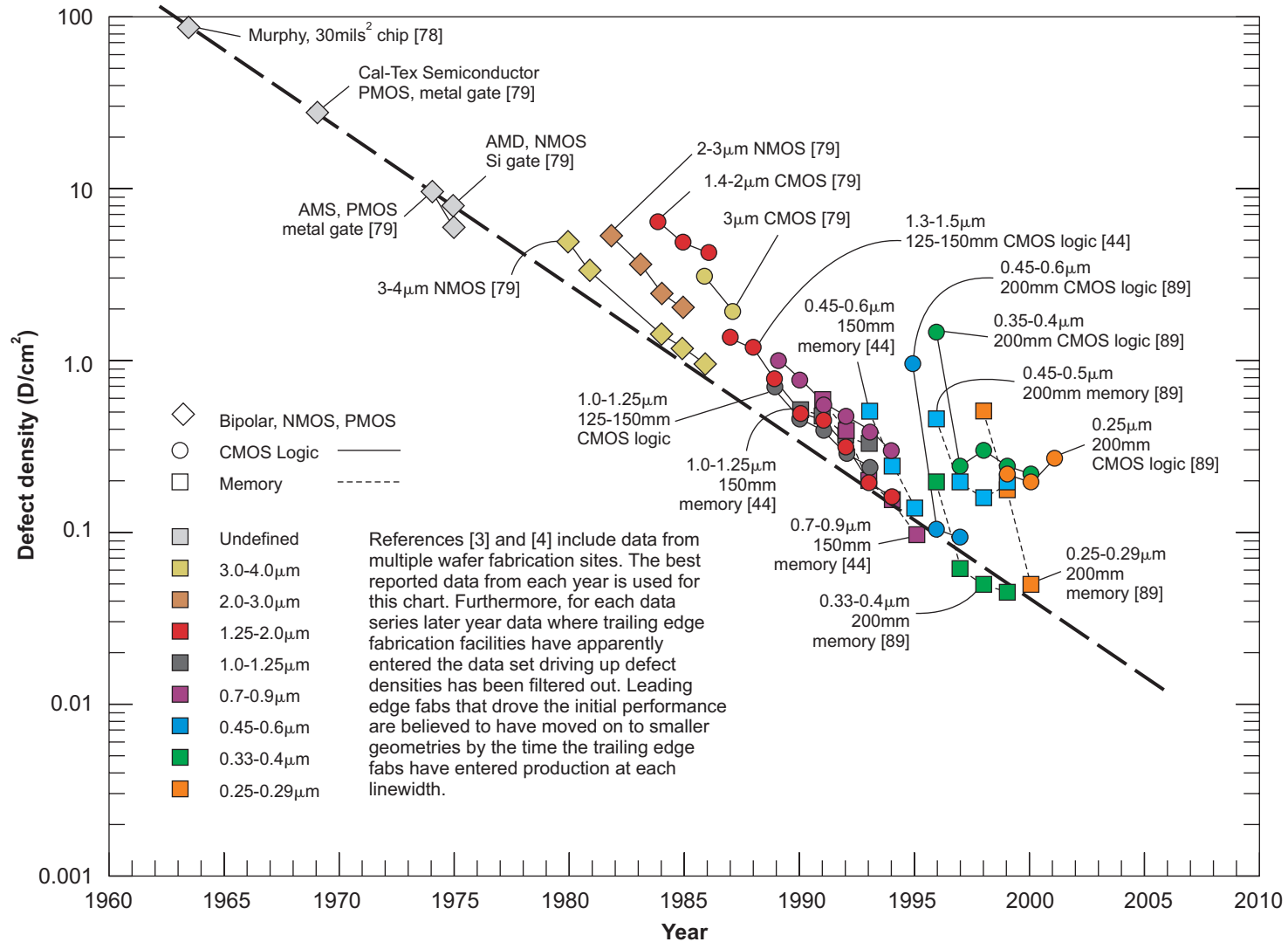


Defect Density Trends

www.icknowledge.com



¹ Philip R. Thomas, "Competitiveness Through Total Cycle Time," McGraw Hill (1990).

² James A. Cunningham, "The Remarkable Trend in Defect Densities and Chip Yields," Semicon. International, p.86, June (1992).

³ Robert C. Leachman ed., "Competitive Semiconductor Manufacturing Survey: Third Report of the Main Phase," UC Berkeley (1996).

⁴ Robert C. Leachman, "Competitive Semiconductor Manufacturing: Final Report from benchmarking Eight-inch, sub-350nm Wafer Fabrication Lines," UC Berkeley (2002).